Notice of References Cited

Application/Control No. 10/760,562	Reexamination	Applicant(s)/Patent Under Reexamination CHEN ET AL.		
Examiner	Art Unit			
Jason M Han	2875	Page 1 of 4		

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-3,868,676	02-1975	Hennessey et al.	345/43
	В	US-3,914,021	10-1975	Nishimura, Izuhiko	349/58
	С	US-4,025,147	05-1977	Van Arsdale et al.	439/634
	D	US-4,545,023	10-1985	Mizzi, Pierre M. A.	708/143
	Ε	US-4,714,983	12-1987	Lang, Warren R.	362/27
	F	US-4,789,224	12-1988	Bougsty, Larry J.	349/65
	G	US-4,975,808	12-1990	Bond et al.	362/31
	Н	US-5,070,431	12-1991	Kitazawa et al.	362/31
	ı	US-5,134,548	07-1992	Turner, Winfield F.	362/29
	J	US-5,166,815	11-1992	Elderfield, David V.	349/64
	К	US-5,272,601	12-1993	McKillip, Robert C.	362/27
	L	US-5,381,309	01-1995	Borchardt, Jerry L.	362/31
	М	US-5,420,710	05-1995	Nanbu, Hajime	349/62

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	υ	
	V	
	w	
	x	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited Application/Control No. | Applicant(s)/Patent Under | Reexamination | CHEN ET AL. | Examiner | Art Unit | Page 2 of 4

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-5,436,745	07-1995	Voisin et al.	349/58
	В	US-5,450,221	09-1995	Owen et al.	349/58
	С	US-5,537,296	07-1996	Kimura et al.	362/31
	D	US-5,539,554	07-1996	Lebby et al.	349/58
	Е	US-5,550,715	08-1996	Hawkins, Jeffrey C.	362/31
	F	US-5,567,042	10-1996	Farchmin et al.	362/241
	G	US-5,654,779	08-1997	Nakayama et al.	349/58
	Н	US-5,661,339	08-1997	Clayton, James E.	257/678
	ı	US-5,769,521	06-1998	Osawa et al.	362/27
	J	US-5,889,568	03-1999	Seraphim et al.	349/73
	к	US-5,889,623	03-1999	Ueda et al.	359/819
	L	US-5,947,578	09-1999	Ayres, John A.	362/31
	М	US-6,036,328	03-2000	Ohtsuki et al.	362/31

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Z					
	0					
	Р					
	Q					_
	R					
	s					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	ט	· ·
	>	2
	W	
	×	·

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination CHEN ET AL. | Examiner | Art Unit | Jason M Han | 2875 | Page 3 of 4

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,068,381	05-2000	Ayres, John A.	362/31
	В	US-6,147,724	11-2000	Yoshii et al.	349/62
	С	US-6,220,741	04-2001	Kawachi et al.	362/561
	D	US-2001/0003504	06-2001	Ishihara et al.	362/31
	E	US-6,268,694	07-2001	Fujimoto, Kazushi	313/491
	F	US-2002/0003595	01-2002	Yazawa, Kazuki	349/65
	G	US-2002/0101729	08-2002	Hayashi et al.	362/84
	Н	US-6,490,016	12-2002	Koura, Shinzi	349/58
	1	US-2002/0181231	12-2002	Luk, John F.	362/240
	J	US-6,498,631	12-2002	Natsuyama, Yoshifumi	349/62
	к	US-6,508,564	01-2003	Kuwabara et al.	362/31
	L	US-6,545,732	04-2003	Nakano, Hiroyuki	349/58
	М	US-2003/0223249	12-2003	Lee et al.	362/561

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	2					
	0					
	Ը					
	σ					
	R					
	s	`				
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
	U							
	٧							
	 W							
	x							

^{*}A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited Application/Control No. 10/760,562 Examiner Jason M Han Applicant(s)/Patent Under Reexamination CHEN ET AL. Page 4 of 4

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,666,567	12-2003	Feldman et al.	362/237
	В	US-6,719,436	04-2004	Lin et al.	362/31
	С	US-2004/0090766	05-2004	Chen, Mi-Chien	362/031
	D	US-6,806,920	10-2004	Hayashi et al.	349/58
	Ε	US-6,814,458	11-2004	Kim et al.	362/31
	F	US-2004/0232853	11-2004	Hur, Jeong-Wook et al.	315/291
	G	US-			
	Н	US-			
	1	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	s					
	Т					·

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	υ	
	٧	
	w	
	x	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.